



Synthetic optical holography for phase resolved Terahertz nano-imaging at sub-50 nm resolution

C. Maissen¹, S. Mastel¹, J. Hesler², S. Hommel³, T. Schweinboeck³, I. Amenabar¹, and R. Hillenbrand^{1,4}



¹CIC nanoGUNE, 20018 Donostia-San Sebastián, Spain ² Diodes Inc., 22901 Charlottesville, USA

³ Infineon Technologies, Failure Analysis 85579 Neubiberg, Germany ⁴ Ikerbasque, Basque Foundation for Science, 48011 Bilbao, Spain

Abstract

We extend synthetic optical holography (SOH) [1] to the THz frequency range for fast, amplitude and phase resolved nano-imaging based on a scattering scanning near-field optical microscopy (s-SNOM). A THz gas laser is used for illumination and the scattered light is interferometrically detected by a Schottky diode operating at room temperature [2]. We demonstrate the systems capabilities on an ion implanted Silicon test structure [3]. Subsequently we image a Au/CsI boundary and find strong frequency dependent material contrast in accordance with a phonon-resonance at 2 THz [4,5].

[1] M. Schnell et al., Nature Communications, 5, 3499, 2014 [2] T. Schweinböck and S. Hommel, Microelectronics Reliability, 54, 2070-2074, 2014 [3] J. Hesler et al. IRMMW-THz 36th International Conference, IEEE 2011 [4] E. Plyler, N. Acquista, JOSA, 48(9), 668-669, 1958. [5] R. Hillenbrand et al., Nature. 418 2002.

Synthetic optical holography

Ion implanted Silicon wafer - its flatness and known carrier density makes it an ideal test sample for s-SNOM





- > Multiplicative background (which persits in the scattered ligth even for high demodulation harmonics) can be removed by SOH
- > We find good agreement of measured s-SNOM phase and amplitude contrast with nominal carrier densities

- SIFIR 50 THz gas laser, discrete lines from 1-6 THz
- collimated beam waist after lens ~ 5 mm
- Imaging using commercial Pt/Ir coated AFM tips (10 μm long) with NeaSNOM microscope
- Phase of reference beam controlled by 300 mm long linear stage
- Schottky diode detector with 0.8 THz 3 dB bandwidth at center frequency of 2.5 THz, large mixing gain due to strong local oscillator (i.e. reference arm)

Schottky Diode Detector



- > s-SNOM at 2.5 THz is sensitive carrier probe at densities from $10^{17} 10^{19} \text{ cm}^{-3}$

Phonon Resonance in Csl Crystal



- Strong, frequency dependent material contrast
- At 2.54 THz signal on CsI below noise level
- At 2.2 THz, CsI is 10x more reflective in the nearfield in respect to Au



- Electric field mixing due to non-linear IV-curve
- Drive diode close to saturation current to enhance square law response
- Linear regime given by $E_{LO} \gg E_{scat}$ (typical LO-power is 1 mW), ideal to detect small, tipscattered signals on top of large far-field background

- At 1.89 THz similar response from CsI and Au
- Measurements are consistent with a phonon in Csl at 2 THz



- All room-temperature tabletop THz-nearfield imaging
- Fast image acquisition thanks to large gain from mixing with local oscillator
- SOH allows to remove multiplicative background which does not vanish by simply demodulating at high harmonics of the tip
- Setup benchmarked with ion implanted dopands in Silicon and phonon resonance in CsI

cmaissen@nanogune.eu

www.nanogune.eu

CIC nanoGUNE Tolosa Hiribidea, 76. E-20018 Donostia - San Sebastián | +34 943 574 000

